



Trace elements analysis of environmental samples with X-rays

Roberto Terzano (IT), Koen Janssens (BE), Ryan Tappero (US), Melissa Anne Denecke (UK),
Gerald Falkenberg (DE), David Paterson (AU), Bradley Miller (US),
Armin Gross (DE) and Fang-Jie Zhao(CN)

The use of X-ray methods for the analysis of trace elements in environmental samples has become a modern tool for scientists around the world. X-ray analyses of trace elements in environmental matrices can be successfully performed both at synchrotron facilities and in the lab, with dedicated instrumentation.

This Symposium aims at informing the audience about the most recent developments in trace elements analysis in environmental samples with X-rays, available both at synchrotron beamlines and as laboratory instrumentation. In particular, the latest developments in X-ray technology (sources, optics, detectors) and sample preparation will be presented as well as new X-ray based analytical methods for the analysis of trace elements in the environment.

In particular, new developments in the fields of X-ray diffraction, X-ray fluorescence, and X-ray absorption will be discussed, both in 2D and 3D applications, with a special emphasis on spatially resolved microscopic and submicroscopic analyses of minor and trace elements in environmental matrices.

The Symposium will be organized in oral and poster sessions, with invited keynote lectures.

The Symposium is co-sponsored by IUPAC (International Union of Pure and Applied Chemistry) - Division VI "Chemistry and the Environment" and by Bruker Nano GmbH.

Three poster prizes will be awarded by IUPAC Division VI to young participants, including an award plaque and prize money.